

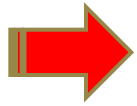
Lighting Up Semiconductor World...

APSYS | CSUPREM | LASTIP | PICS3D | PROCOM | CROSSLIGHTVIEW

Crosslight TCAD Simulation of Micro-LED

CROSSLIGHT
Software Inc.

Contents



- Advanced models and capabilities
- Effect of sidewall defects
- MQW barrier design
- AC modulation

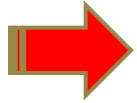


Advanced models

- Self-consistent MQW model based on $k \cdot p$ band structure calculations
- Quantum tunneling for EBL leakage
- Various trap models for the sidewall defects
- Self-heating thermal models
- AC/transient analysis

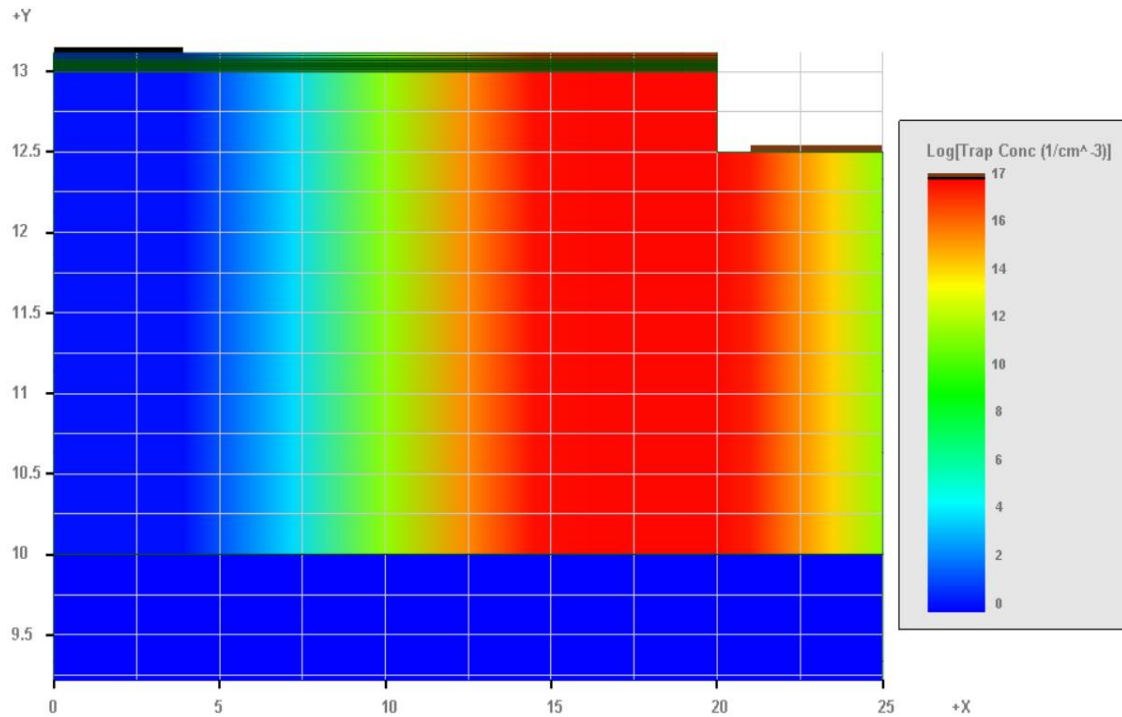


Contents



- Advanced models and capabilities
- Effect of sidewall defects
- MQW barrier design
- AC modulation





```

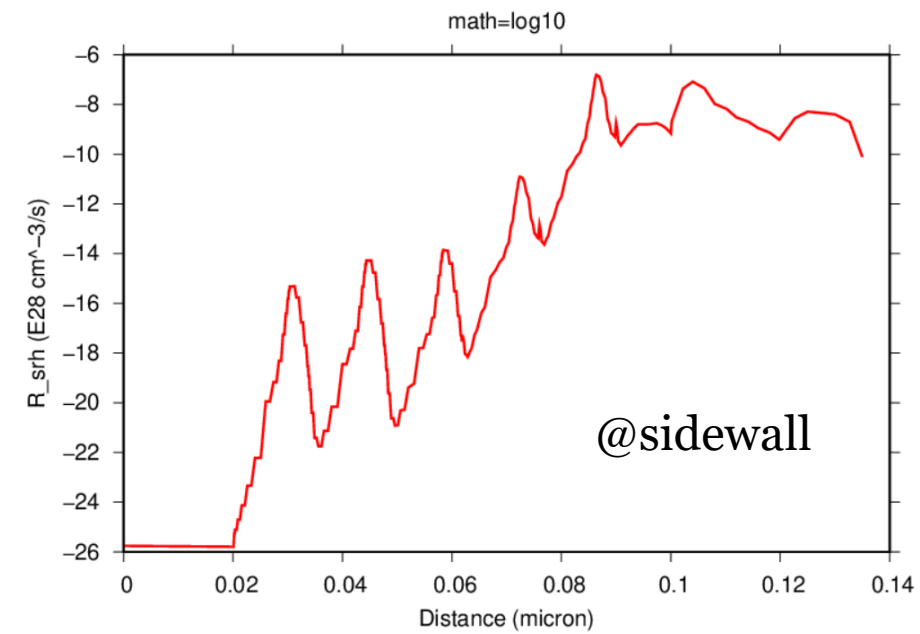
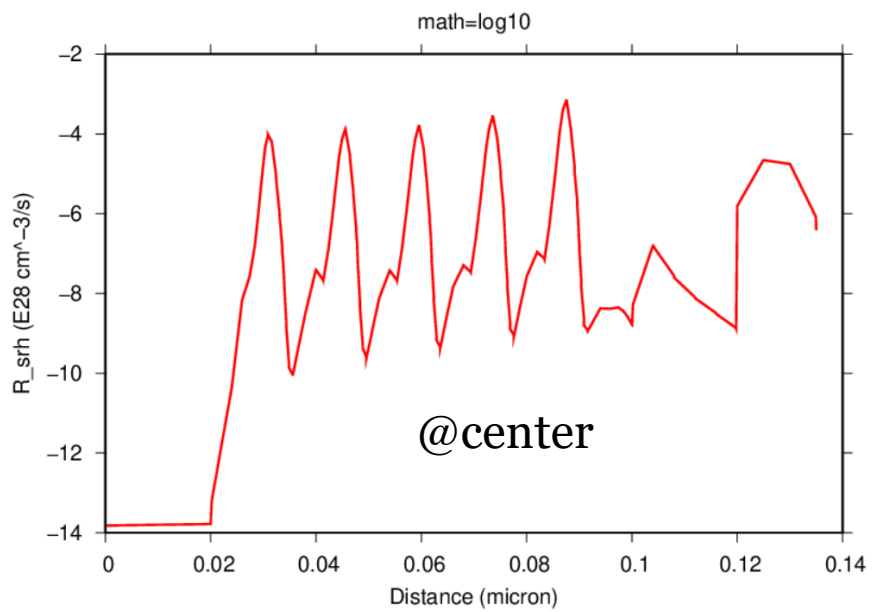
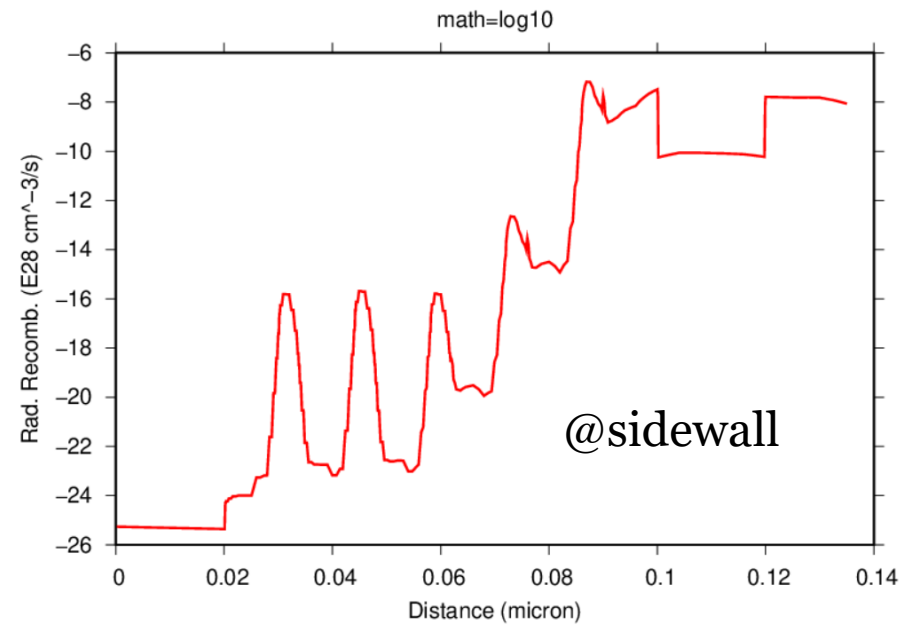
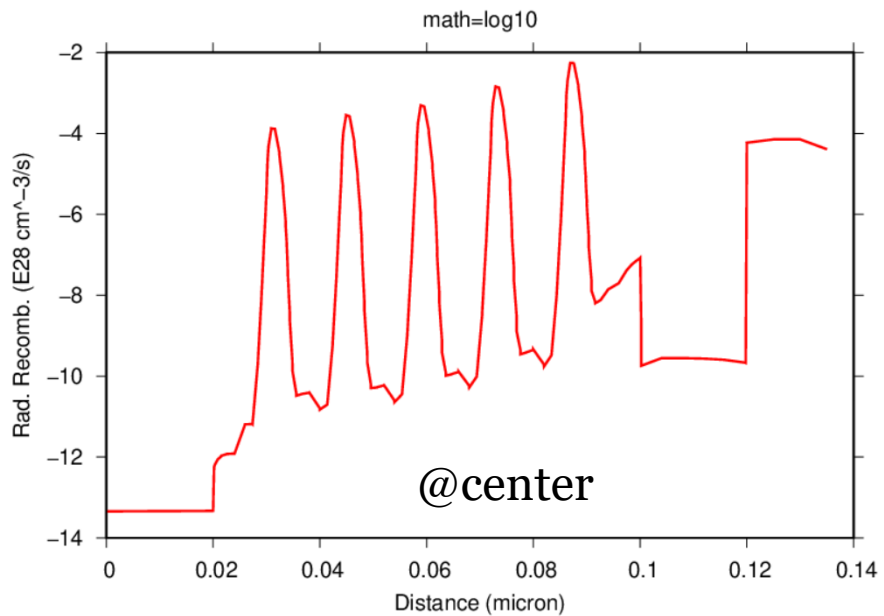
start_loop symbol=%m value_from=1 value_to=9
trap_ncap_2 value=1.e-17 mater=%m
trap_pcap_2 value=1.e-17 mater=%m
trap_level_2 value=1.3 mater=%m
trap_ncap_3 value=1.e-17 mater=%m
trap_pcap_3 value=1.e-17 mater=%m
trap_level_3 value=1.6 mater=%m
end_loop symbol=%m value_from=1 value_to=9

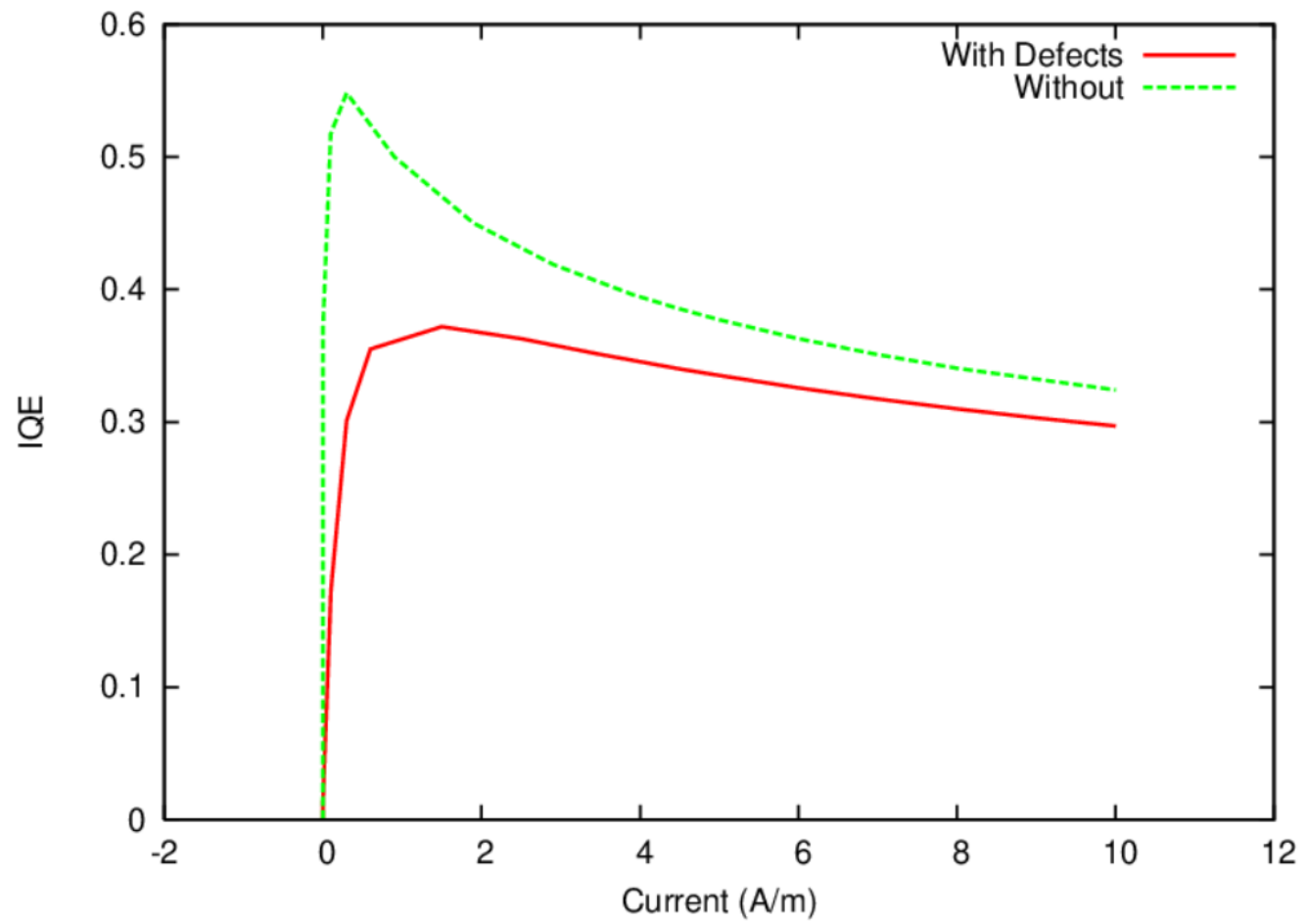
```

```

$ ---traps for defects near the vertical wall of uLED
$ since trap_1 is reserved for SRH lifetime setting, it is
$ better we define additional traps using trap_2, trap_3,
$ etc....
$ trap level measured from conduction band
$ 1/lifetime=
$ trap_density*thermal_velocity*trap_cap_cross_section
$ 1/sec=(1/m**3)*(m/s)*trap_cap
$ roughly vtherm=1.e5 m/s, trap_cap=1nm**2,
conc=1.e23 m**-3
$ 1/tau=1.e23*1.e5*1.e-18=1.e10 => tau=0.1ns
$
doping impurity=trap_2 charge_type=donor &&
  max_conc=1.0e23 level=1.3 &&
  x_prof=[15.00, 20, 1., 1.] &&
  y_prof=[0, 50, 0.1 0.1]
doping impurity=trap_3 charge_type=acceptor &&
  max_conc=1.0e23 level=1.6 &&
  x_prof=[15.00, 20, 1., 1.] &&
  y_prof=[0, 50, 0.1 0.1]

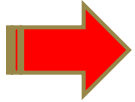
```

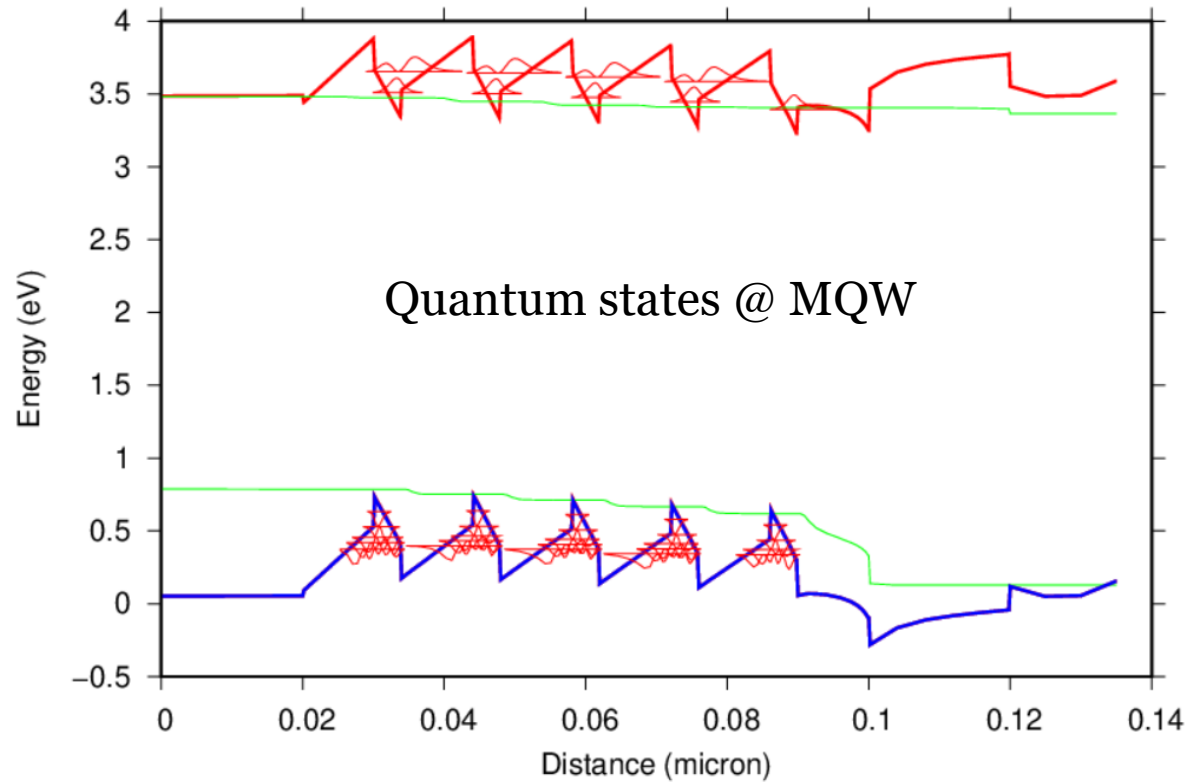




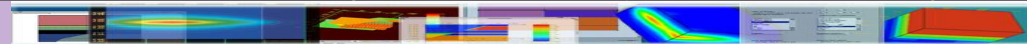
Contents

- Advanced models and capabilities
- Effect of sidewall defects
- MQW barrier design
- AC modulation

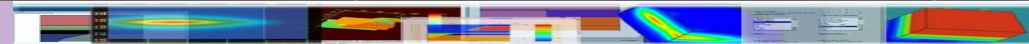
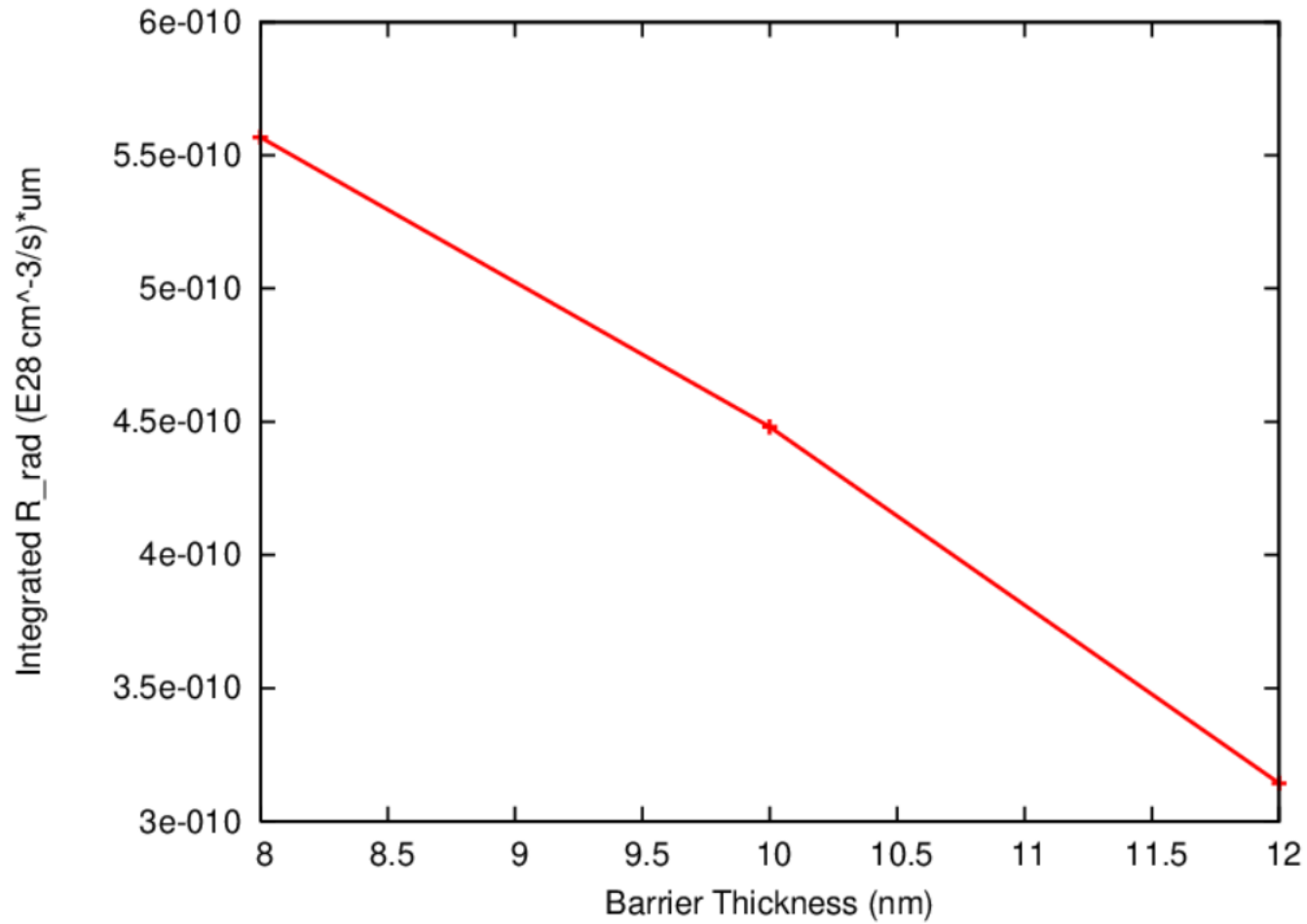




Big question: if the sidewall defects are not dense enough to quench all radiative recombination/emission there, how do we design the MQW to enhance it?

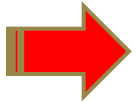


Smaller barrier seems enhance radiative emission from defect region



Contents

- Advanced models and capabilities
- Effect of sidewall defects
- MQW barrier design
- AC modulation



New application for uLED: free space telecom

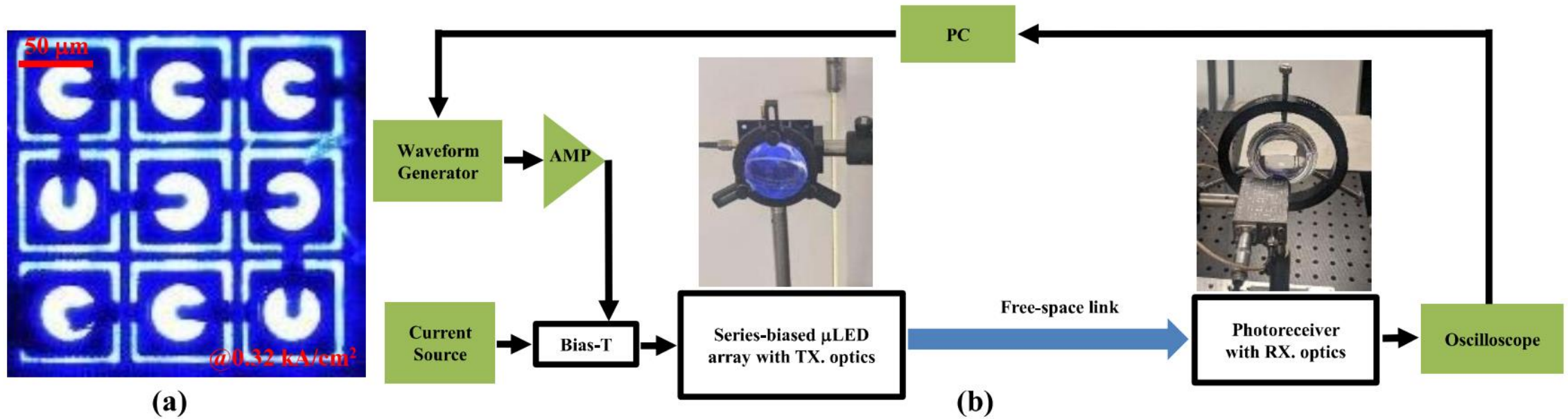


Fig. 1. (a) Plan-view optical micrograph image of the fabricated series-biased μ LED array operating at 0.32 kA/cm^2 ; (b) schematic diagram of the setup for different-distance VLC measurements, the optical images of the transmitter and receiver modules are inserted as well.

How to compute the modulation characteristics of uLED

After setting the DC bias, impose a fast Gaussian pulse to probe how the uLED respond to it.

```
scan var=current_1 value_to=50. &&  
  init_step=0.1 min_step=1e-3 max_step=3
```

```
scan var=time value_to=10.e-9 &&  
  var2=current_1 function_label2=gs_func &&  
  init_step=0.01e-9 max_step=0.1e-9  
scan_function label=gs_func type=gaussian gsn_dt=2.e-9 &&  
gsn_s1=50 gsn_s2=60
```

```
scan var=time value_to=100.e-9 max_step=2.e-9 &&  
var2=current_1 value2_to=50.
```



Convert impulse response using Fourier transform

\$ modulation response is

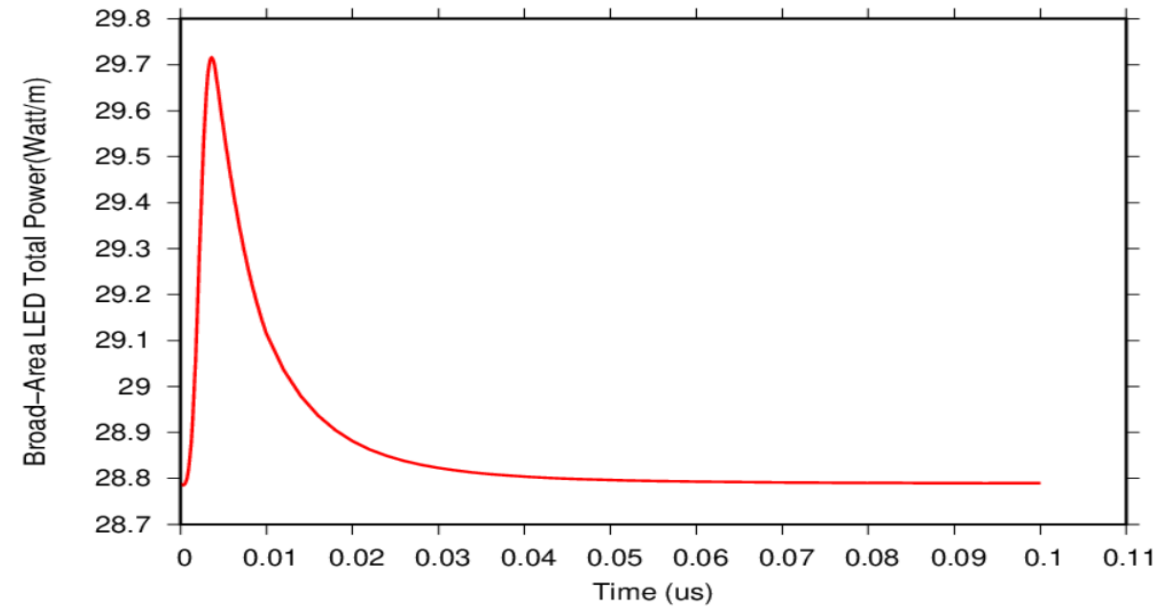
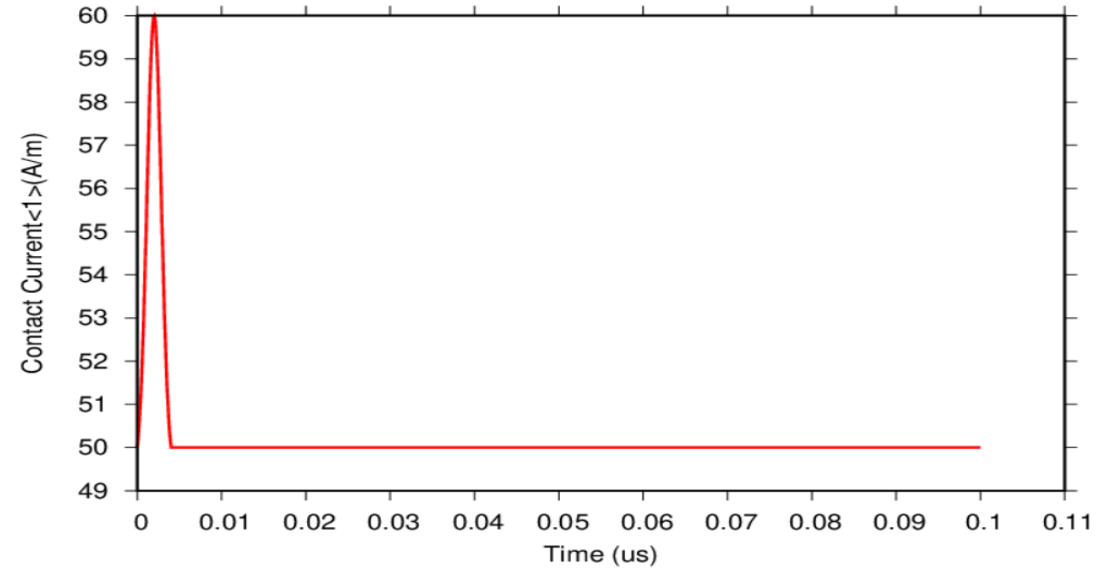
```
2*log(led_power(freq)/current_1(freq))
```

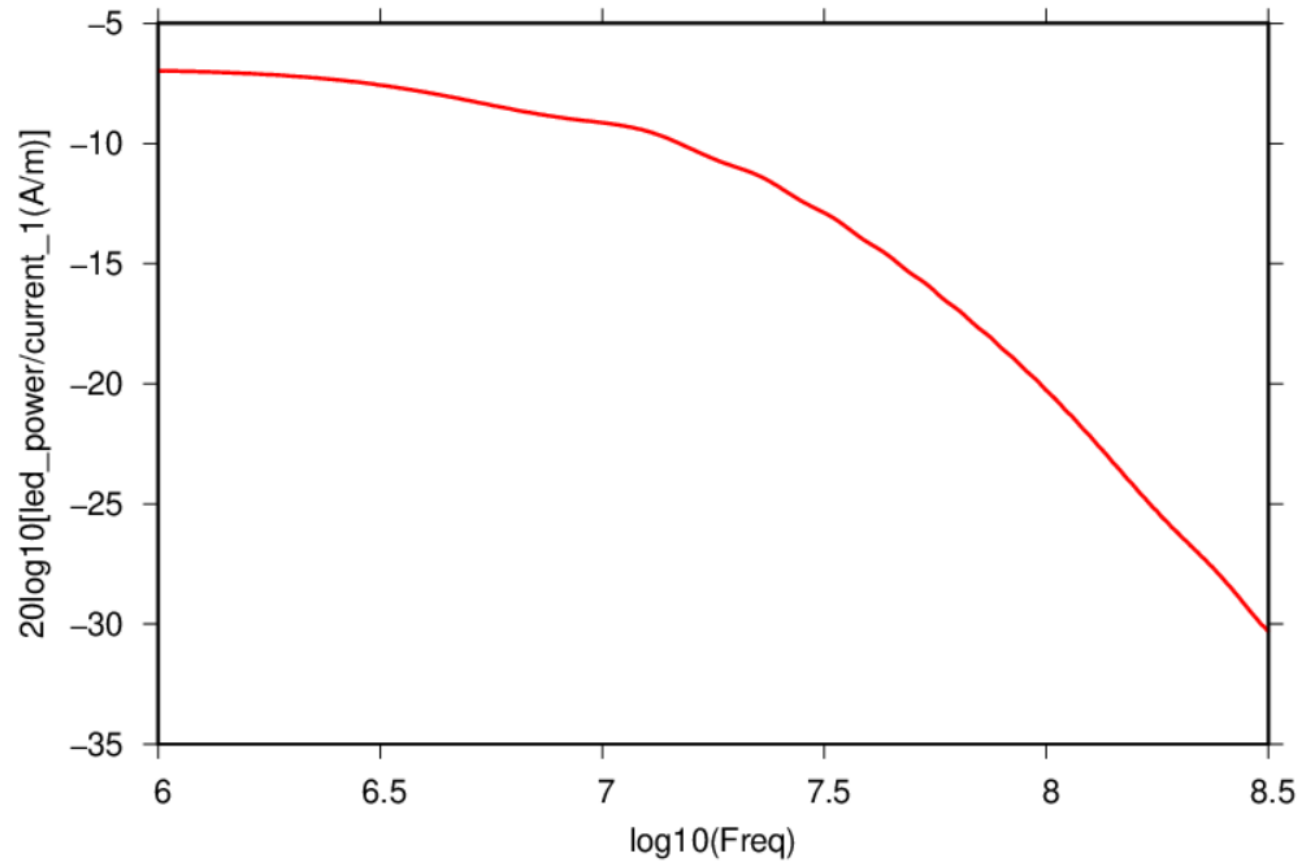
```
plot_scan scan_var=time variable=current_1
```

```
plot_scan scan_var=time variable=led_power
```

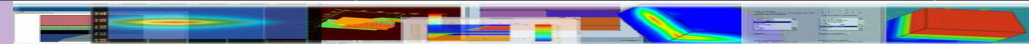
```
fourier_power input_var=current_1 output_var=led_power &&
```

```
log_freq=yes freq_start=6 freq_end=8.5
```





Response sensitive to injection current and uLED side, as well as defect properties



Conclusions

- ➔ Crosslight TCAD tool convenient and powerful for analysis of uLED
- ➔ The sidewall defects should be characterized using details trap parameters in both spatial and energy distribution
- ➔ Impulse response can be used to obtain modulation response for telecom applications



Thanks for your
attention!



Creators of Award Winning Software

CROSSLIGHT

Software Inc.

